



<p><b>Searched</b></p> 	<p>Application/Control No.</p> <p>10601015</p>	<p>Applicant(s)/Patent Under Reexamination</p> <p>AIK, ERIC TEH GIM</p>
	<p>Examiner</p> <p>Rossoshek, Helen</p>	<p>Art Unit</p> <p>2825</p>

Class	Sub Class	Date	Examiner
716	3-5,10,11,14,17,18	8/1/2005	HR
714	725	8/1/2005	HR
702	117	8/1/2005	HR

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<b>Search Notes</b>  	Application/Control No.  10601015	Applicant(s)/Patent Under Reexamination  AIK, ERIC TEH GIM
	Examiner Rossoshek, Helen	Art Unit 2825

Notes	Date	Examiner
EAST (USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB)	8/1/2005	HR
IEEE	8/1/2005	HR

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